

# CAT25C01, CAT25C02, CAT25C04

# 1K/2K/4K SPI Serial CMOS EEPROM



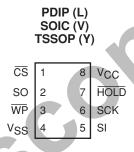
#### **FEATURES**

- 10 MHz SPI compatible
- 1.8 to 5.5 volt operation
- 16-byte page write buffer
- Hardware and software protection
- Block write protection– Protect 1/4, 1/2 or all of EEPROM array
- Low power CMOS technology
- SPI modes (0,0 & 1,1)
- Industrial temperature range
- 1,000,000 program/erase cycles
- 100 year data retention
- Self-timed write cycle
- RoHS compliant "Green" & "Gold" 8-pin PDIP, SOIC and TSSOP packages

#### **DESCRIPTION**

The CAT25C01/02/04 is a 1K/2K/4K Bit SPI Serial CMOS EEPROM internally organized as 128x8/256x8/512x8 bits. Catalyst's advanced CMOS Technology substantially reduces device power requirements. The CAT25C01/02/04 features a 16-byte page write buffer. The device operates via the SPI bus serial interface and is enabled though a Chip Select (CS). In addition to the Chip Select, the clock input (SCK), data in (SI) and data out (SO) are required to access the device. The HOLD pin may be used to suspend any serial communication without resetting the serial sequence. The CAT25C01/02/04 is designed with software and hardware write protection features including Block Write protection. The device is available in 8-pin DIP, 8-pin SOIC and 8-pin TSSOP packages.

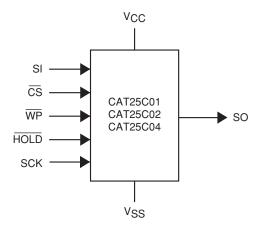
#### PIN CONFIGURATION



# PIN FUNCTIONS

Pin Name	Function
SO	Serial Data Output
SCK	Serial Clock
WP	Write Protect
Vcc	+1.8V to +5.5V Power Supply
V <sub>SS</sub>	Ground
CS	Chip Select
SI	Serial Data Input
HOLD	Suspends Serial Input

#### **FUNCTIONAL SYMBOL**





#### **ABSOLUTE MAXIMUM RATINGS\***

Storage Temperature	-65°C to +150°C
Voltage on Any Pin with Respect to Ground <sup>(1)</sup>	-0.5 V to +6.5 V

<sup>\*</sup> Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions outside of those listed in the operational sections of this specification is not implied. Exposure to any absolute maximum rating for extended periods may affect device performance and reliability.

### **RELIABILITY CHARACTERISTICS(2)**

Symbol	Parameter	Min	Units
N <sub>END</sub> (*)	Endurance	1,000,000	Program/ Erase Cycles
T <sub>DR</sub>	Data Retention	100	Years

<sup>(\*)</sup> Page Mode, V<sub>CC</sub> = 5 V, 25°C

#### **D.C. OPERATING CHARACTERISTICS**

 $V_{CC} = 1.8 \text{ V}$  to 5.5 V,  $T_A = -40^{\circ}\text{C}$  to 85°C, unless otherwise specified.

Symbol	Parameter	Test Conditions	Min	Max	Units
I <sub>CC</sub>	Supply Current	Read or Write at 5 MHz		1	mA
I <sub>SB</sub>	Standby Current	All I/O Pins at GND or $V_{CC}$ , $\overline{CS} = V_{CC}$		2	μΑ
IL	I/O Pin Leakage	Pin at GND or V <sub>CC</sub>		2	μΑ
V <sub>IL</sub>	Input Low Voltage		-0.5	V <sub>CC</sub> x 0.3	V
V <sub>IH</sub>	Input High Voltage		V <sub>CC</sub> x 0.7	V <sub>CC</sub> + 0.5	V
V <sub>OL1</sub>	Output Low Voltage	$V_{CC} > 2.5 \text{ V}, I_{OL} = 3.0 \text{ mA}$		0.4	V
V <sub>OL2</sub>	Output Low Voltage	$V_{CC} > 1.8 \text{ V}, I_{OL} = 1.0 \text{ mA}$		0.2	V

#### PIN IMPEDANCE CHARACTERISTICS

 $T_A = 25$ °C, f = 1 MHz,  $V_{CC} = 5$  V

Symbol	Parameter	Conditions	Min	Max	Units
C <sub>IN</sub> (2)	SDA I/O Pin Capacitance	$V_{IN} = 0 V$		8	pF
C <sub>IN</sub> <sup>(2)</sup>	Input Capacitance (other pins)	$V_{IN} = 0 V$		6	pF
Z <sub>WPL</sub>	WP Input Low Impedance	V <sub>IN</sub> < 0.5 V	5	70	kΩ
I <sub>LWPH</sub>	WP Input High Leakage	$V_{IN} > V_{CC} \times 0.7$		2	μΑ

## Note:

<sup>(1)</sup> The DC input voltage on any pin should not be lower than -0.5 V or higher than  $V_{CC} + 0.5$  V. During transitions, the voltage on any pin may undershoot to no less than -1.5 V or overshoot to no more than  $V_{CC} + 1.5$  V, for periods of less than 20 ns.

<sup>(2)</sup> These parameters are tested initially and after a design or process change that affects the parameter according to appropriate AEC-Q100 and JEDEC test methods.



#### **A.C. CHARACTERISTICS**

		CAT25CXX-1.8			CAT2	5CXX			
		1.8V-	1.8V-5.5V		2.5V-5.5V		4.5V-5.5V		Test
SYMBOL	PARAMETER	Min.	Max.	Min.	Max.	Min.	Max.	UNITS	Conditions
tsu	Data Setup Time	50		20		20		ns	
t <sub>H</sub>	Data Hold Time	50		20		20		ns	
twH	SCK High Time	250		75		40		ns	
t <sub>WL</sub>	SCK Low Time	250		75		40		ns	
fsck	Clock Frequency	DC	1	DC	5	DC	10	MHz	
t <sub>LZ</sub>	HOLD to Output Low Z		50		50		50	ns	
t <sub>RI</sub> <sup>(1)</sup>	Input Rise Time		2		2		2	μs	
t <sub>FI</sub> <sup>(1)</sup>	Input Fall Time		2		2		2	μs	
t <sub>HD</sub>	HOLD Setup Time	100		40		40		ns	
t <sub>CD</sub>	HOLD Hold Time	100		40		40		ns	
twc <sup>(4)</sup>	Write Cycle Time		5		5		5	ms	C <sub>L</sub> = 50pF
tv	Output Valid from Clock Low		250		75		40	ns	(note 2)
t <sub>HO</sub>	Output Hold Time	0		0		0		ns	
t <sub>DIS</sub>	Output Disable Time		250		75		75	ns	
t <sub>HZ</sub>	HOLD to Output High Z		150		50		50	ns	
tcs	CS High Time	500		100		100		ns	
tcss	CS Setup Time	500		100		100		ns	
tcsH	CS Hold Time	500		100		100		ns	
twps	WP Setup Time	150		50		50		ns	
twpH	WP Hold Time	150		50		50		ns	

# Power-Up Timing<sup>(1)(3)</sup>

Symbol	Symbol Parameter		Max.	Units
tpur		Power-up to Read Operation	1	ms
tpuw		Power-up to Write Operation	1	ms

#### NOTE

(1) This parameter is tested initially and after a design or process change that affects the parameter.

(2) AC Test Conditions:

Input Pulse Voltages: 0.3V<sub>CC</sub> to 0.7V<sub>CC</sub>

Input rise and fall times: ≤10ns

Input and output reference voltages: 0.5V<sub>CC</sub>

Output load: current source I<sub>OL</sub> max/I<sub>OH</sub> max; C<sub>L</sub>=50pF

- (3) tPUR and tPUW are the delays required from the time V<sub>CC</sub> is stable until the specified operation can be initiated.
- (4) two is the time from the rising edge of  $\overline{\text{CS}}$  after a valid write sequence to the end of the internal write cycle.



#### **FUNCTIONAL DESCRIPTION**

The CAT25C01/02/04 supports the SPI bus data transmission protocol. The synchronous Serial Peripheral Interface (SPI) helps the CAT25C01/02/04 to interface directly with many of today's popular microcontrollers. The CAT25C01/02/04 contains an 8-bit instruction register. (The instruction set and the operation codes are detailed in the instruction set table)

After the device is selected with  $\overline{CS}$  going low, the first byte will be received. The part is accessed via the SI pin, with data being clocked in on the rising edge of SCK. The first byte contains one of the six op-codes that define the operation to be performed.

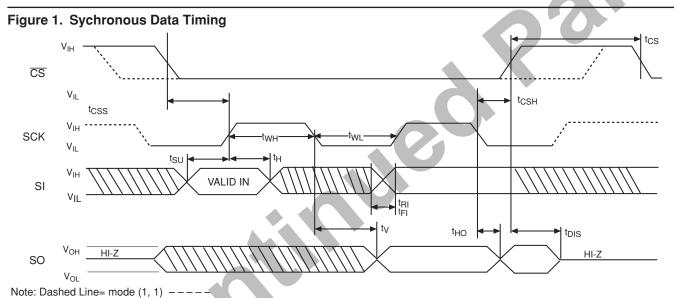
### PIN DESCRIPTION

#### SI: Serial Input

SI is the serial data input pin. This pin is used to input all opcodes, byte addresses, and data to be written to the CAT25010/20/40. Input data is latched on the rising edge of the serial clock for SPI modes (0, 0 & 1, 1).

# SO: Serial Output

SO is the serial data output pin. This pin is used to transfer data out of the CAT25C01/02/04. During a read cycle, data is shifted out on the falling edge of the serial clock for SPI modes (0,0 & 1,1).



#### Note: Dashed Line= mode (1, 1)

#### **INSTRUCTION SET**

Instruction	Opcode	Operation
WREN	0000 0110	Enable Write Operations
WRDI	0000 0100	Disable Write Operations
RDSR	0000 0101	Read Status Register
WRSR	0000 0001	Write Status Register
READ	0000 X011 <sup>(1)</sup>	Read Data from Memory
WRITE	0000 X010 <sup>(1)</sup>	Write Data to Memory

### Note:

(1) X=0 for CAT25C01, CAT25C02. X=A8 for CAT25C04.



SCK: Serial Clock

SCK is the serial clock pin. This pin is used to synchronize the communication between the microcontroller and the CAT25C01/02/04. Opcodes, byte addresses, or data present on the SI pin are latched on the rising edge of the SCK. Data on the SO pin is updated on the falling edge of the SCK for SPI modes (0,0 & 1,1).

**CS**: Chip Select

CS is the Chip select pin. CS low enables the CAT25C01/02/04 and CS high disables the CAT25C01/02/04. CS high takes the SO output pin to high impedance and forces the devices into a Standby Mode (unless an internal write operation is underway) The CAT25C01/02/04 draws ZERO current in the Standby mode. A high to low transition on CS is required prior to any sequence being initiated. A low to high transition on CS after a valid write sequence is what initiates an internal write cycle.

WP: Write Protect

WP is the Write Protect pin. The Write Protect pin will allow normal read/write operations when held high.

When  $\overline{WP}$  is tied low and the WPEN bit in the status register is set to "1", all write operations to the status register are inhibited.  $\overline{WP}$  going low while  $\overline{CS}$  is still low will interrupt a write to the status register. If the internal write cycle has already been initiated,  $\overline{WP}$  going low will have no effect on any write operation to the status register. The  $\overline{WP}$  pin function is blocked when the WPEN bit is set to 0. Figure 10 illustrates the  $\overline{WP}$  timing sequence during a write operation.

**HOLD**: Hold

The HOLD pin is used to pause transmission to the CAT25C01/20/40 while in the middle of a serial sequence without having to re-transmit entire sequence at a later time. To pause, HOLD must be brought low while SCK is low. The SO pin is in a high impedance state during the time the part is paused, and transitions on the SI pins will be ignored. To resume communication, HOLD is brought high, while SCK is low. (HOLD should be held high any time this function is not being used.) HOLD may be tied high directly to VCC or tied to VCC through a resistor. Figure 9 illustrates hold timing sequence.

### STATUS REGISTER

7	6	5	4	3	2	1	0
WPEN	1	1	1	BP1	BP0	WEL	RDY

#### **BLOCK PROTECTION BITS**

Status Register Bits		Array Address	Protection
BP1	BP0	Protected	
0	0	None	No Protection
0	1	CAT25C01: 60-7F CAT25C02: C0-FF CAT25C04: 180-1FF	Quarter Array Protection
1	0	CAT25C01: 40-7F CAT25C02: 80-FF CAT25C04: 100-1FF	Half Array Protection
	1	CAT25C01: 00-7F CAT25C02: 00-FF CAT25C04: 000-1FF	Full Array Protection

#### WRITE PROTECT ENABLE OPERATION

WPEN	WP	WEL	Protected Blocks	Unprotected Blocks	Status Register
0	Х	0	Protected	Protected	Protected
0	Х	1	Protected	Writable	Writable
1	Low	0	Protected	Protected	Protected
1	Low	1	Protected	Writable	Protected
Χ	High	0	Protected	Protected	Protected
Х	High	1	Protected	Writable	Writable



#### STATUS REGISTER

The Status Register indicates the status of the device. The  $\overline{\text{RDY}}$  (Ready) bit indicates whether the CAT25C01/02/04 is busy with a write operation. When set to 1 a write cycle is in progress and when set to 0 the device indicates it is ready. This bit is read only. The WEL (Write Enable) bit indicates the status of the write enable latch. When set to 1, the device is in a Write Enable state and when set to 0 the device is in a Write Disable state. The WEL bit can only be set by the WREN instruction and can be reset by the WRDI instruction.

The BP0 and BP1 (Block Protect) bits indicate which blocks are currently protected. These bits are set by the user issuing the WRSR instruction. The user is allowed to protect quarter of the memory, half of the memory or the entire memory by setting these bits. Once protected, the user may only read from the protected portion of the array. These bits are non-volatile.

The WPEN (Write Protect Enable) is an enable bit for the  $\overline{WP}$  pin. The  $\overline{WP}$  pin and WPEN bit in the status register control the programmable hardware write protect feature. Hardware write protection is enabled when  $\overline{WP}$  is low and WPEN bit is set to high. The user cannot write

to the status register, (including the block protect bits and the WPEN bit) and the block protected sections in the memory array when the chip is hardware write protected. Only the sections of the memory array that are not block protected can be written. Hardware write protection is disabled when either  $\overline{\text{WP}}$  pin is high or the WPEN bit is zero.

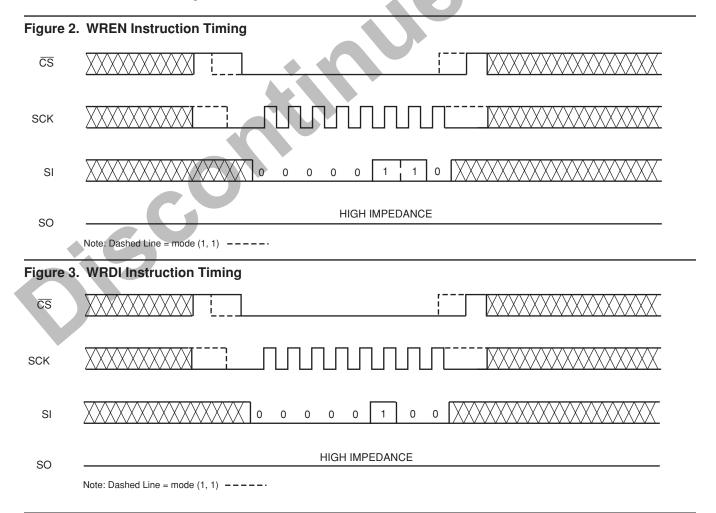
#### **DEVICE OPERATION**

#### Write Enable and Disable

The CAT25C01/02/04 contains a write enable latch. This latch must be set before any write operation. The device powers up in a write disable state when  $V_{\rm CC}$  is applied. WREN instruction will enable writes (set the latch) to the device. WRDI instruction will disable writes (reset the latch) to the device. Disabling writes will protect the device against inadvertent writes.

## **READ Sequence**

The part is selected by pulling  $\overline{CS}$  low. The 8-bit read instruction is transmitted to the CAT25C01/02/04, followed by the 8-bit address for CAT25C01/02/04 (for the CAT25C04, bit 3 of the read data instruction contains address A8).





After the correct read instruction and address are sent, the data stored in the memory at the selected address is shifted out on the SO pin. The data stored in the memory at the next address can be read sequentially by continuing to provide clock pulses. The internal address pointer is automatically incremented to the next higher address after each byte of data is shifted out. When the highest address is reached, the address counter rolls over to 0000h allowing the read cycle to be continued indefinitely. The read operation is terminated by pulling the  $\overline{\text{CS}}$  high. To read the status register, RDSR instruction should be sent. The contents of the status register are shifted out on the SO line. The status register may be read at any time even during a write cycle. Read sequece is illustrated in Figure 4. Reading status register is illustrated in Figure 5.

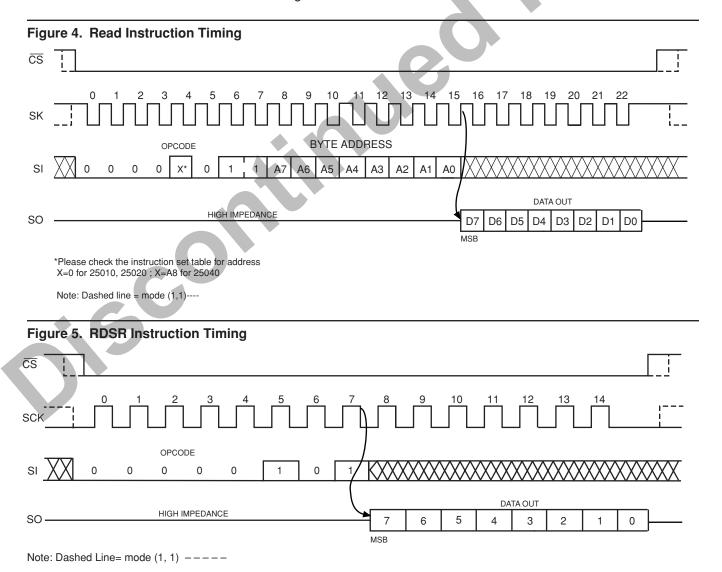
#### **WRITE Sequence**

The CAT25C01/02/04 powers up in a Write Disable state. Prior to any write instructions, the WREN instruction must be sent to CAT25C01/02/04. The device goes into

Write enable state by pulling the  $\overline{CS}$  low and then clocking the WREN instruction into CAT25C01/02/04. The  $\overline{CS}$  must be brought high after the WREN instruction to enable writes to the device. If the write operation is initiated immediately after the WREN instruction without  $\overline{CS}$  being brought high, the data will not be written to the array because the write enable latch will not have been properly set. Also, for a successful write operation the address of the memory location(s) to be programmed must be outside the protected address field location selected by the block protection level.

#### **Byte Write**

Once the device is in a Write Enable state, the user may proceed with a write sequence by setting the  $\overline{CS}$  low, issuing a write instruction via the SI line, followed by the 8-bit address for CAT25C01/02/04 (for the 25C04, bit 3 of the read data instruction contains address A8). Programming will start after the  $\overline{CS}$  is brought high. Figure 6 illustrates byte write sequence.





During an internal write cycle, all commands will be ignored except the RDSR (Read Status Register) instruction.

The Status Register can be read to determine if the write cycle is still in progress. If Bit 0 of the Status Register is set at 1, write cycle is in progress. If Bit 0 is set at 0, the device is ready for the next instruction.

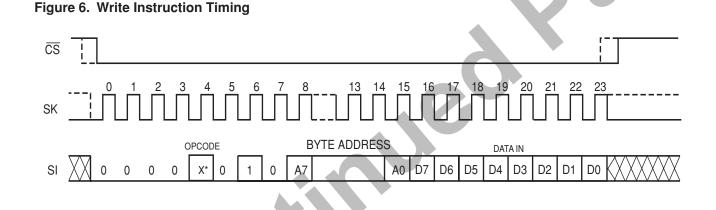
#### **Page Write**

The CAT25C01/02/04 features page write capability. After the initial byte, the host may continue to write up to 16 bytes of data to the CAT25C01/02/04. After each byte of data received, lower order address bits are internally incremented by one; the high order bits of

HIGH IMPEDANCE

address will remain constant. The only restriction is that the X (X=16 for CAT25C01/02/04) bytes must reside on the same page. If the address counter reaches the end of the page and clock continues, the counter will "roll over" to the first address of the page and overwrite any data that may have been written. The CAT25C01/02/04 is automatically returned to the write disable state at the completion of the write cycle. Figure 8 illustrates the page write sequence.

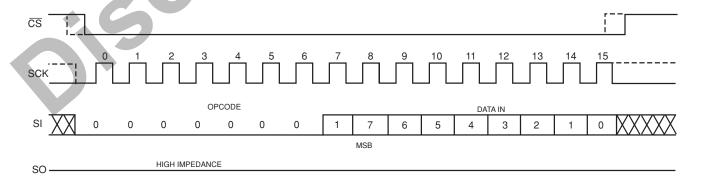
To write to the status register, the WRSR instruction should be sent. Only Bit 2, Bit 3 and Bit 7 of the status register can be written using the WRSR instruction. Figure 7 illustrates the sequence of writing to status register.



Note: Dashed Line= mode (1, 1) ----\*X=0 for 25010, 25020; X=A8 for 25040

Figure 7. WRSR Timing

SO



Note: Dashed Line= mode (1, 1) -----



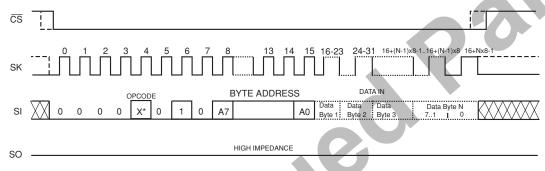
#### **DESIGN CONSIDERATIONS**

The CAT25C01/02/04 powers up in a write disable state and in a low power standby mode. A WREN instruction must be issued to perform any writes to the device after power up. Also,on power up  $\overline{CS}$  should be brought low to enter a ready state and receive an instruction. After a successful byte/page write or status register write, the CAT25C01/02/04 goes into a write disable mode.  $\overline{CS}$  must be set high after the proper number of clock cycles to start an internal write cycle. Access to the array during an internal write cycle is ignored and program-

ming is continued. On power up, SO is in a high impedance. If an invalid op code is received, no data will be shifted into the CAT25C01/02/04, and the serial output pin (SO) will remain in a high impedance state until the falling edge of  $\overline{CS}$  is detected again.

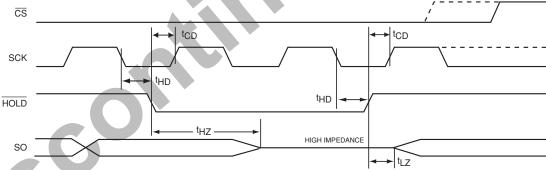
When powering down, the supply should be taken down to 0V, so that the CAT25C01/02/04 will be reset when power is ramped back up. If this is not possible, then, following a brown-out episode, the CAT25C01/02/04 can be reset by refreshing the contents of the Status Register (See Application Note AN10).

Figure 8. Page Write Instruction Timing



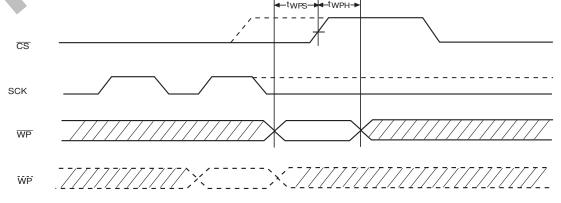
Note: Dashed Line= mode (1, 1) - - - - \*X=0 for CAT25C01, CAT25C02; X=A8 for CAT25C04

Figure 9. HOLD Timing



Note: Dashed Line= mode (1, 1) -----

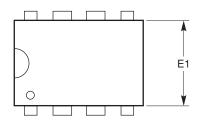
Figure 10. WP Timing

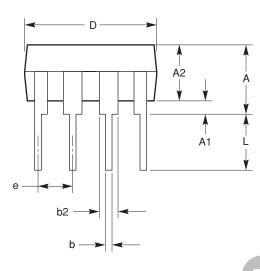


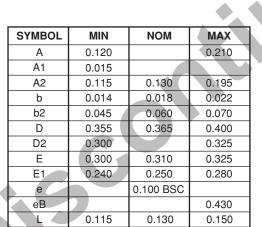
Note: Dashed Line= mode (1, 1) - - - -

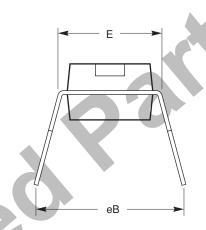


# 8-LEAD 300 MIL WIDE PLASTIC DIP (L)









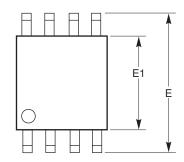
24C02\_8-LEAD\_DIP\_(300P).eps

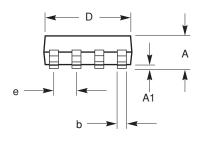
#### Notes:

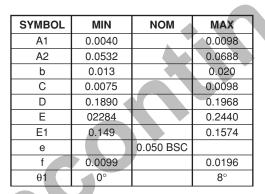
- 1. Complies with JEDEC Standard MS001.
- 2. All dimensions are in inches.
- 3. Dimensioning and tolerancing per ANSI Y14.5M-1982

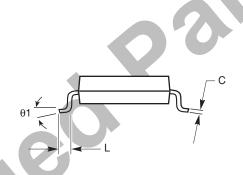


# 8-LEAD 150 MIL WIDE SOIC (V)









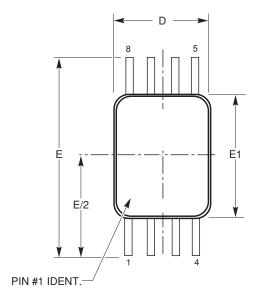
24C02\_8-LEAD\_SOIC.eps

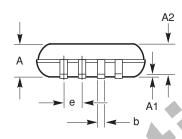
## Notes:

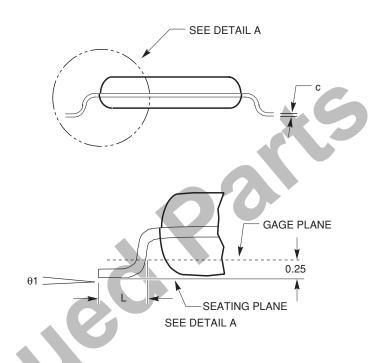
- 1. Complies with JEDEC specification MS-012 dimensions.
- 2. All linear dimensions in millimeters.



# 8-LEAD TSSOP (Y)







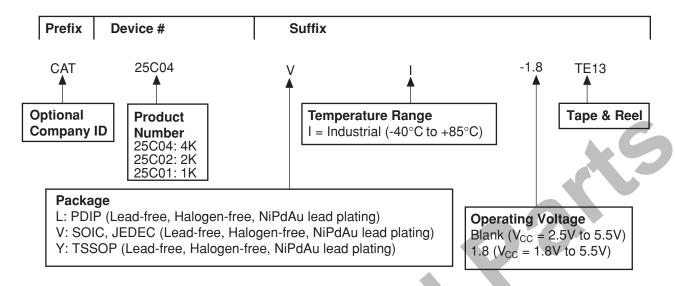
SYMBOL	MIN	NOM	MAX
Α			1.20
A1	0.05		0.15
A2	0.80	0.90	1.05
b	0.19		0.30
С	0.09		0.20
D	2.90	3.00	3.10
П	6.30	6.4	6.50
E1	4.30	4.40	4.50
е		0.65 BSC	
L	0.50	0.60	0.75
θ1	0.00		8.00

#### Notes:

1. All dimensions in millimeters.



#### **ORDERING INFORMATION**



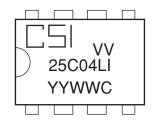
#### Notes

(1) The device used in the above example is a CAT25C04VI-1.8TE13 (SOIC, Industrial Temperature, 1.8 Volt to 5.5 Volt Operating Voltage, Tape & Reel)



#### **PACKAGE MARKING**

#### 8-Lead PDIP



CSI = Catalyst Semiconductor, Inc.

25C04L = Device Code

I = Temperature Range

YY = Production Year

WW = Production Week

C = Product Revision

VV = Voltage Range

1.8V - 5.5V = 18

2.5V - 5.5V = Blank

#### 8-Lead SOIC



CSI = Catalyst Semiconductor, Inc

25C04V = Device Code

I = Temperature Range

YY = Production Year

WW = Production Week

C = Product Revision

VV = Voltage Range

1.8V - 5.5V = 18

2.5V - 5.5V = Blank

#### 8-Lead TSSOP



Y = Production Year

M = Production Month

C = Die Revision

25Y04 = Device Code

I = Industrial Temperature Range

V = Voltage Range

1.8V - 5.5V = 8

2.5V - 5.5V = Blank

## Notes:

(1) The circle on the package marking indicates the location of Pin 1.

#### **REVISION HISTORY**

Date	Rev.	Reason
10/13/05	А	Initial Issue



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